## **Power MOSFET**

# 60 V, 155 m $\Omega$ , Single N-Channel Logic Level, SOT-23

#### **Features**

- Small Footprint Industry Standard Surface Mount SOT-23 Package
- Low R<sub>DS(on)</sub> for Low Conduction Losses and Improved Efficiency
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Param	Symbol	Value	Unit		
Drain-to-Source Voltage			V <sub>DSS</sub>	60	V
Gate-to-Source Voltage	V <sub>GS</sub>	±20	V		
Continuous Drain	Steady	T <sub>A</sub> = 25°C	I <sub>D</sub>	2.2	Α
Current R <sub>ΨJ-mb</sub> (Notes 1, 2, 3, and 4)	State	T <sub>A</sub> = 100°C		1.6	
Power Dissipation		T <sub>A</sub> = 25°C	P <sub>D</sub>	1.5	W
R <sub>ΨJ-mb</sub> (Notes 1 and 3)		T <sub>A</sub> = 100°C		0.6	
Continuous Drain	Steady State	T <sub>A</sub> = 25°C	I <sub>D</sub>	1.7	Α
Current R <sub>0JA</sub> (Note 1, 2, 3, and 4)	State	T <sub>A</sub> = 100°C		1.2	
Power Dissipation R <sub>θJA</sub>		T <sub>A</sub> = 25°C	$P_{D}$	0.9	W
(Notes 1 and 3)		T <sub>A</sub> = 100°C		0.4	
Pulsed Drain Current		= 25°C, = 10 μs	I <sub>DM</sub>	27	Α
Operating Junction and S	T <sub>J</sub> , T <sub>stg</sub>	–55 to 150	°C		
Source Current (Body Die	Is	1.9	Α		
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Psi  $(\Psi)$  is used as required per JESD51-12 for packages in which substantially less than 100% of the heat flows to single case surface.
- 3. Surface-mounted on FR4 board using a 650 mm2, 2 oz. Cu pad.
- 4. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

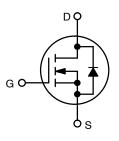


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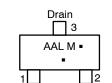
V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> TYP	I <sub>D</sub> MAX	
60 V	155 m $\Omega$ @ 10 V	2.2 A	
33 1	205 mΩ @ 4.5 V	/ .	

#### N-Channel





SOT-23 CASE 318 STYLE 21



Source

MARKING DIAGRAM/ PIN ASSIGNMENT

AAL = Device Code

M = Date Code\*

■ Pb-Free Package

(Note: Microdot may be in either location)

\*Date Code orientation may vary depending upon manufacturing location.

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NVR5198NLT1G	SOT-23 (Pb-Free)	3000 / Tape & Reel
NVR5198NLT3G	SOT-23 (Pb-Free)	10000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

### THERMAL RESISTANCE RATINGS

Parameter		Max	Unit
Junction-to-Lead #3 - Drain (Notes 2 and 3)		86	°C/W
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	139	°C/W

#### **ELECTRICAL CHARACTERISTICS** (T<sub>1</sub> = 25°C unless otherwise noted)

Parameter	Symbol	Test Conditions		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS}$ = 0 V, $I_D$ = 250 $\mu A$		60			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>	Reference to 25°C, $I_D$ = 250 $\mu A$			70		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C			1.0	μΑ
		$V_{DS} = 60 \text{ V}$	T <sub>J</sub> = 125°C			10	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V	GS = ±20 V			±100	nA
ON CHARACTERISTICS (Note 5)	•			•	•	•	
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}$ ,	I <sub>D</sub> = 250 μA	1.5		2.5	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>	Reference to 25	i°C, I <sub>D</sub> = 250 μA		-6.5		mV/°C
Drain-to-Source On-Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 1 A		107	155	mΩ
		V <sub>GS</sub> = 4.5	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 1 A		142	205	1
Forward Transconductance	9 <sub>FS</sub>	V <sub>DS</sub> = 5.0	V, I <sub>D</sub> = 1 A		3		S
CHARGES, CAPACITANCES & GATE	RESISTANCE	:				1	I
Input Capacitance	C <sub>iss</sub>				182		pF
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0 \text{ V}, \text{ f}$	= 1.0 MHz,		25		1
Reverse Transfer Capacitance	C <sub>rss</sub>	V <sub>DS</sub> = 25 V			16		1
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>DS</sub> = 48 V,	V <sub>GS</sub> = 4.5 V		2.8		nC
	,	$I_D = 1 A$	V <sub>GS</sub> = 10 V		5.1		
Threshold Gate Charge	Q <sub>G(TH)</sub>				0.3		1
Gate-to-Source Charge	Q <sub>GS</sub>	V <sub>DS</sub> = 48	V I <sub>D</sub> = 1 Δ		0.8		1
Gate-to-Drain Charge	$Q_{GD}$	V <sub>GS</sub> =	10 V		1.5		1
Plateau Voltage	$V_{GP}$				3.1		V
Gate Resistance	$R_{G}$				8		Ω
SWITCHING CHARACTERISTICS (No	ote 6)					1	ı
Turn-On Delay Time	t <sub>d(on)</sub>				5		ns
Rise Time	t <sub>r</sub>	Vpo - 30 V	Voc - 10 V		7		1
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{DS} = 30 \text{ V, } V_{GS} = 10 \text{ V,}$ $I_{D} = 1 \text{ A, } R_{G} = 10 \Omega$			13		1
Fall Time	t <sub>f</sub>				2		1
DRAIN-SOURCE DIODE CHARACTE	RISTICS			1			1
Forward Diode Voltage	$V_{SD}$	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.8	1.2	V
- -		I <sub>S</sub> = 1 A	T <sub>J</sub> = 125°C		0.6		1
Reverse Recovery Time	t <sub>rr</sub>	1 .,			12		ns
Charge Time	t <sub>a</sub>	$I_{S} = 1 A_{dc}, V_{GS} = 0 V_{dc},$ $dI_{S}/dt = 100 A/\mu s$			9		1
Discharge Time	t <sub>b</sub>				3		1
Reverse Recovery Stored Charge	Q <sub>RR</sub>			<u> </u>	6		nC

<sup>5.</sup> Pulse Test: Pulse Width  $\leq$  300  $\mu$ s, Duty Cycle  $\leq$  2%.

<sup>6.</sup> Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**

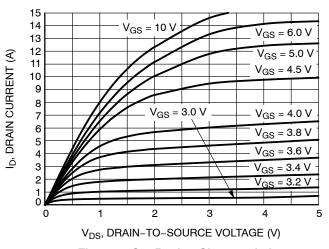


Figure 1. On-Region Characteristics

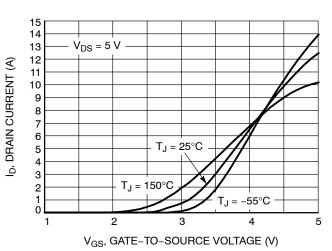


Figure 2. Transfer Characteristics

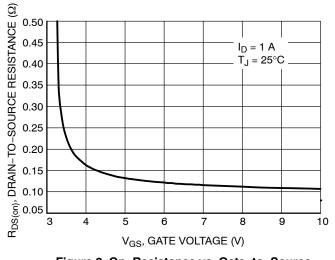


Figure 3. On-Resistance vs. Gate-to-Source Voltage

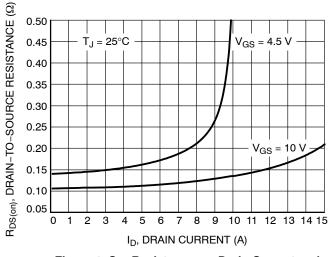


Figure 4. On-Resistance vs. Drain Current and **Gate Voltage** 

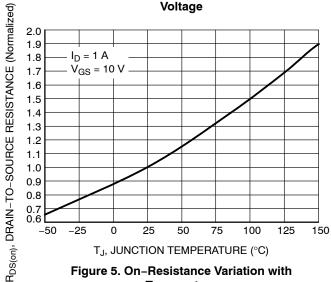


Figure 5. On-Resistance Variation with **Temperature** 

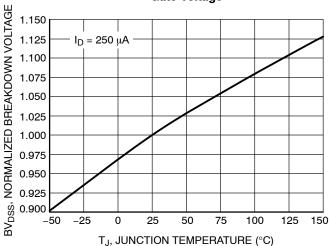


Figure 6. Breakdown Voltage Variation with **Temperature** 

#### **TYPICAL CHARACTERISTICS**

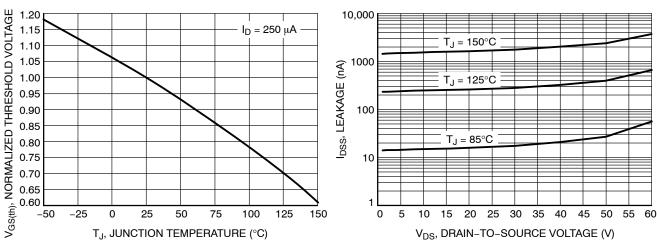


Figure 7. Threshold Voltage Variation with Temperature

Figure 8. Drain-to-Source Leakage Current vs. Voltage

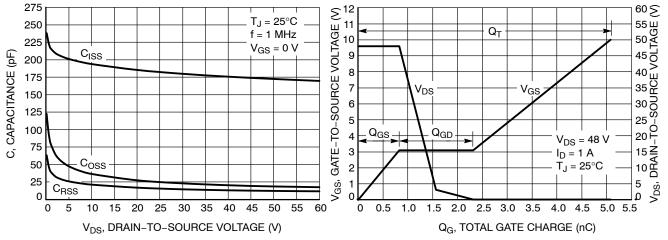


Figure 9. Capacitance Variation

Figure 10. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

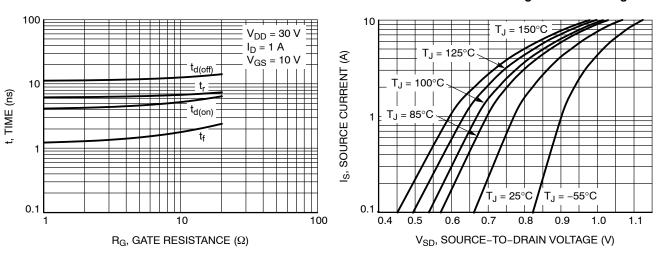


Figure 11. Resistive Switching Time Variation vs. Gate Resistance

Figure 12. Diode Forward Voltage vs. Current

### **TYPICAL CHARACTERISTICS**

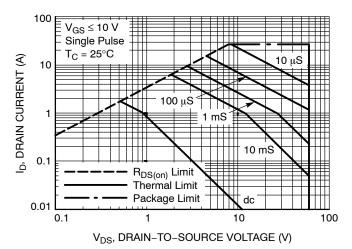


Figure 13. Maximum Rated Forward Biased

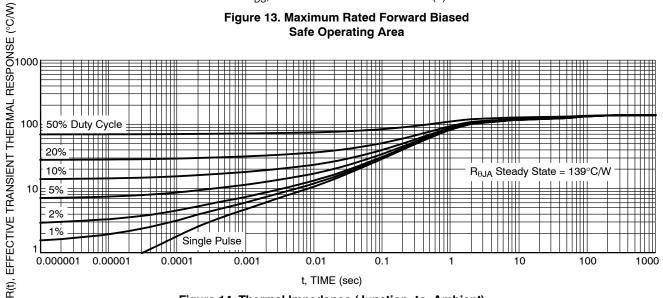
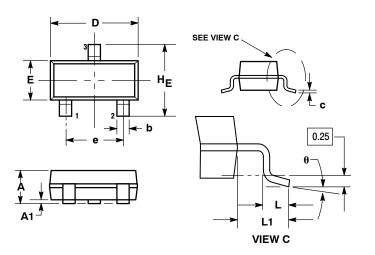


Figure 14. Thermal Impedance (Junction-to-Ambient)

#### PACKAGE DIMENSIONS

#### SOT-23 (TO-236) CASE 318-08 **ISSUE AP**



- NOTES:

  1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

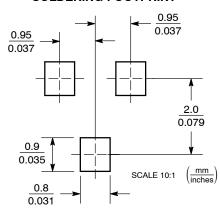
  2. CONTROLLING DIMENSION: INCH.

  3. MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH
  THICKNESS. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF BASE MATERIAL
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS

	MILLIMETERS			INCHES			
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.89	1.00	1.11	0.035	0.040	0.044	
A1	0.01	0.06	0.10	0.001	0.002	0.004	
b	0.37	0.44	0.50	0.015	0.018	0.020	
С	0.09	0.13	0.18	0.003	0.005	0.007	
D	2.80	2.90	3.04	0.110	0.114	0.120	
E	1.20	1.30	1.40	0.047	0.051	0.055	
е	1.78	1.90	2.04	0.070	0.075	0.081	
L	0.10	0.20	0.30	0.004	0.008	0.012	
L1	0.35	0.54	0.69	0.014	0.021	0.029	
HE	2.10	2.40	2.64	0.083	0.094	0.104	
θ	0°		10°	0°		10°	

STYLE 21: PIN 1. GATE SOURCE 3 DRAIN

### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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